


<b>Search Notes</b>  	<b>Application/Control No.</b>  10583926	<b>Applicant(s)/Patent Under Reexamination</b>  FUNG ET AL.
	<b>Examiner</b>  CHRISTOPHER H YAEN	<b>Art Unit</b>  1643

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
stic sequence search: 18,10, 99,104, 115, 117, 123, 135	10/12/2009	chy
palm inventor search	10/12/09	chy

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
	stic seq search: 18,10, 99,104, 115, 117, 123, 135	10/12/09	chy

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